www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
Shen Keng Dist, New Taipei City, Taiwan
TEL: +886-2-26620988
FAX: +886-2-26620488

Product/Process Change Notification

PCN#	Effective Date	Issue Date
2017-05-25C-04	2017/8/25	2017/5/25

PCN Classification	Product Category
Major	Mosfet

Subject

Production process change from lead free to halogen free.

Affected Product(s)

SOT-723 Package of Mosfet, inclouding SSN3043. SSN3134K. SSN3139K and SSN3541.

Description of Change(s)

To meet EU environment requirement, we implement halogen free to our products.

Content of Change(s)

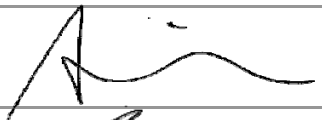
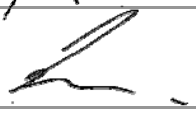
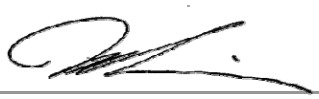
Adding “-C” to each part number.

Impact(s)

N/A

Attachment(s)

SGS report. Reliability report.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

測試報告
Test Report

號碼(No.) : KA/2016/61540　日期(Date) : 2016/07/04　頁數(Page) : 1 of 21

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

以下測試樣品係由客戶送樣，且由客戶聲稱並經客戶確認如下
(The following samples was/were submitted and identified by/on behalf of the client as) :

樣品名稱(Sample Description)	:	EXPOXY MOLDING COMPOUND
樣品型號(Style/Item No.)	:	ELER-8-SERIES
收件日期(Sample Receiving Date)	:	2016/06/27
測試期間(Testing Period)	:	2016/06/27 TO 2016/07/04
送樣廠商(Sample Submitted By)	:	義典科技股份有限公司 (E'DALE (WUXI-E'DALE) TECHNOLOGY CO., LTD.)

==========

測試需求(Test Requested) : 依據客戶要求，參考RoHS 2011/65/EU Annex II 指令進行鎘，鉛，汞，六價鉻，多溴聯苯，多溴聯苯醚測試.(As specified by client, with reference to RoHS Directive 2011/65/EU Annex II to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs contents in the submitted sample.)

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).

結論(Conclusion) : 根據客戶所提供的樣品，其鎘，鉛，汞，六價鉻，多溴聯苯，多溴聯苯醚的測試結果符合RoHS指令2002/95/EC的更新指令2011/65/EU之要求 (Based on the performed tests on submitted samples, the test results of Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs comply with the limits as set by RoHS Directive 2011/65/EU Annex II; recasting 2002/95/EC.)

Ray Chang Ph.D. / Manager-Tec
Signed for and on behalf of
SGS Taiwan Limited
Chemical Laboratory-Kaohsiung

測試報告
Test Report

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試結果(Test Results)

測試部位(PART NAME) NO.1 : 黑色 EXPOXY MOLDING COMPOUND (BLACK EXPOXY MOLDING COMPOUND)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.	100
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.	1000
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.	1000
六價鉻 / Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	參考IEC 62321: 2008方法, 用UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.	1000
六價鉻 / Hexavalent Chromium Cr(VI)(#2)	$\mu g/cm^2$	參考IEC 62321-7-1:2015，以UV-VIS檢測. / With reference to IEC 62321-7-1:2015 and performed by by UV-VIS.	0.10	n.d.	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321-6: 2015方法, 以氣相層析儀/質譜儀檢測. / With reference to IEC 62321-6: 2015 and performed by GC/MS.	-	n.d.	1000
一溴聯苯 / Monobromobiphenyl			5	n.d.	-
二溴聯苯 / Dibromobiphenyl			5	n.d.	-
三溴聯苯 / Tribromobiphenyl			5	n.d.	-
四溴聯苯 / Tetrabromobiphenyl			5	n.d.	-
五溴聯苯 / Pentabromobiphenyl			5	n.d.	-
六溴聯苯 / Hexabromobiphenyl			5	n.d.	-
七溴聯苯 / Heptabromobiphenyl			5	n.d.	-
八溴聯苯 / Octabromobiphenyl			5	n.d.	-
九溴聯苯 / Nonabromobiphenyl			5	n.d.	-
十溴聯苯 / Decabromobiphenyl			5	n.d.	-
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	參考IEC 62321-6: 2015方法, 以氣相層析儀/質譜儀檢測. / With reference to IEC 62321-6: 2015 and performed by GC/MS.	-	n.d.	1000
一溴聯苯醚 / Monobromodiphenyl ether			5	n.d.	-
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.	-
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.	-
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.	-
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.	-
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.	-
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.	-
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.	-
九溴聯苯醚 / Nonabromodiphenyl ether			5	n.d.	-
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.	-
砷 / Arsenic (As)	mg/kg	參考US EPA 3052方法, 用感應藕合電漿原子發射光譜儀 (ICP-AES) 檢測砷含量. / With reference to US EPA Method 3052 for Arsenic Content. Analysis was performed by ICP-AES.	2	n.d.	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
銻 / Antimony (Sb)	mg/kg	參考US EPA 3052方法, 用感應藕合電漿原子發射光譜儀檢測銻含量. / With reference to US EPA Method 3052 for Antimony Content. Analysis was performed by ICP-AES.	2	n.d.	-
磷 / Phosphorus (P)	mg/kg	參考US EPA 3052方法, 用感應藕合電漿原子發射光譜儀檢測磷含量. / With reference to US EPA Method 3052 for Phosphorus Content. Analysis was performed by ICP-AES.	2	118	-
鈹 / Beryllium (Be)	mg/kg	參考US EPA 3052方法, 用感應藕合電漿原子發射光譜儀檢測鈹含量. / With reference to US EPA Method 3052 for Beryllium Content. Analysis was performed by ICP-AES.	2	n.d.	-
聚氯乙烯 / PVC	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	-	Negative	-
紅磷 / Red phosphorus	**	本測試以熱裂解儀分析. / Analysis was performed by Pyrolyzer-GC/MS.	-	Negative	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS)	mg/kg	參考US EPA 3550C: 2007方法, 以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.	-
全氟辛酸(銨) / PFOA (CAS No.: 335-67-1)	mg/kg	參考US EPA 3550C: 2007方法, 以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007. Analysis was performed by LC/MS.	10	n.d.	-
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α- HBCDD, β- HBCDD, γ- HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.	-
四溴雙酚-A / Tetrabromobisphenol A (TBBP-A) (CAS No.: 79-94-7)	mg/kg	參考RSTS-E&E-121方法, 以液相層析/質譜儀分析. / With reference to RSTS-E&E-121. Analysis was performed by LC/MS.	10	n.d.	-
雙酚 A / Bisphenol A (CAS No.: 80-05-7)	mg/kg	參考RSTS-HL-229-1方法, 以液相層析/質譜儀檢測. / With reference to RSTS-HL-229-1 method. Analysis was performed by LC/MS.	1	n.d.	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
多環芳香烴 / Polynuclear Aromatic Hydrocarbons (PAHs)					
苊 / Acenaphthene (CAS No.: 83-32-9)	mg/kg	參考AfPS GS 2014:01 PAK方法，以氣相層析/質譜儀檢測. / With reference to AfPS GS 2014:01 PAK method. Analysis was performed by GC/MS.	0.2	n.d.	-
苊烯 / Acenaphthylene (CAS No.: 208-96-8)			0.2	n.d.	-
蒽 / Anthracene (CAS No.: 120-12-7)			0.2	n.d.	-
苯駢蒽 / Benzo[a]anthracene (CAS No.: 56-55-3)			0.2	n.d.	-
苯駢(a)芘 / Benzo[a]pyrene (CAS No.: 50-32-8)			0.2	n.d.	-
苯(b)苯駢芴 / Benzo[b]fluoranthene (CAS No.: 205-99-2)			0.2	n.d.	-
苯駢苝 / Benzo[g,h,i]perylene (CAS No.: 191-24-2)			0.2	n.d.	-
苯(k)苯駢芴 / Benzo[k]fluoranthene (CAS No.: 207-08-9)			0.2	n.d.	-
Chrysene (CAS No.: 218-01-9)			0.2	n.d.	-
二苯駢蒽 / Dibenzo[a,h]anthracene (CAS No.: 53-70-3)			0.2	n.d.	-
苯駢芴 / Fluoranthene (CAS No.: 206-44-0)			0.2	n.d.	-
芴 / Fluorene (CAS No.: 86-73-7)			0.2	n.d.	-
茚酮芘 / Indeno[1,2,3-c,d] pyrene (CAS No.: 193-39-5)			0.2	n.d.	-
萘 / Naphthalene (CAS No.: 91-20-3)			0.2	n.d.	-
菲 / Phenanthrene (CAS No.: 85-01-8)			0.2	n.d.	-
芘 / Pyrene (CAS No.: 129-00-0)			0.2	n.d.	-
苯(j)苯駢芴 / Benzo[j]fluoranthene (CAS No.: 205-82-3)			0.2	n.d.	-
苯駢(e)芘 / Benzo[e]pyrene (CAS No.: 192-97-2)			0.2	n.d.	-
多環芳香烴18項總和 / Sum of 18 PAHs	mg/kg	-	-	n.d.	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測極限值 (MDL)	結果 (Result) NO.1	法規限值 (Limit)
鹵素 / Halogen					
鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.	-
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	89.6	-
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.	-
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.	-
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg	參考IEC 62321-8 (111/321/CD)，以氣相層析儀/質譜儀檢測之. / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.	1000
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg		50	n.d.	1000
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg		50	n.d.	1000
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg		50	n.d.	1000
鄰苯二甲酸二異壬酯 / DINP (Di-isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	mg/kg		50	n.d.	-

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

備註(Note):

1. mg/kg = ppm；0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. **= Qualitative analysis (No Unit) 定性分析(無單位)
6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
7. 聚氯乙烯、紅磷測試由SGS其他實驗室執行 (The PVC & Red Phosphorus test was subcontracted to other SGS Laboratory.)
8. (#2) =
   a. 當六價鉻結果大於0.13 μg/cm², 表示樣品表層含有六價鉻. / The sample is positive for Cr(VI) if the Cr(VI) concentration is greater than 0.13 μg/cm². The sample coating is considered to contain Cr(VI).
   b. 當六價鉻結果爲n.d. (濃度小於0.10 μg/cm²), 表示表層不含六價鉻. / The sample is negative for Cr(VI) if Cr(VI) is n.d. (concentration less than 0.10 μg/cm²). The coating is considered a non-Cr(VI) based coating
   c. 當六價鉻結果介於 0.10 及 0.13 μg/cm² 時, 無法確定塗層是否含有六價鉻. / The result between 0.10 μg/cm² and 0.13 μg/cm² is considered to be inconclusive - unavoidable coating variations may influence the determination.

PFOS參考資訊(Reference Information) : 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm), 在半成品、成品或零部件中不得超過0.1%(1000ppm), 在紡織品或塗層材料中不得超過1μg/m²。(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above 1μg/m².)

全氟辛烷磺酸指全氟辛烷磺酸和它的衍生物包括全氟辛烷磺酸, 全氟辛基磺醯胺, N-甲基全氟辛烷磺酰胺, N-乙基全氟辛烷磺酰胺, N-甲基全氟辛基磺酰基氨基乙醇, N-乙基全氟辛基磺酰基氨基乙醇。(PFOS refer to Perfluorooctanesulfonic acid and its derivatives including Perfluoroctanesulfonic acid, Perfluoroctane sulfonamide, N-Methylperfluoroctane sulfonamide, N-Ethylperfluoroctane sulfonamide, N-Methylperfluoroctane sulfonamidoethanol and N-Ethylperfluoroctane sulfonamidoethanol.)

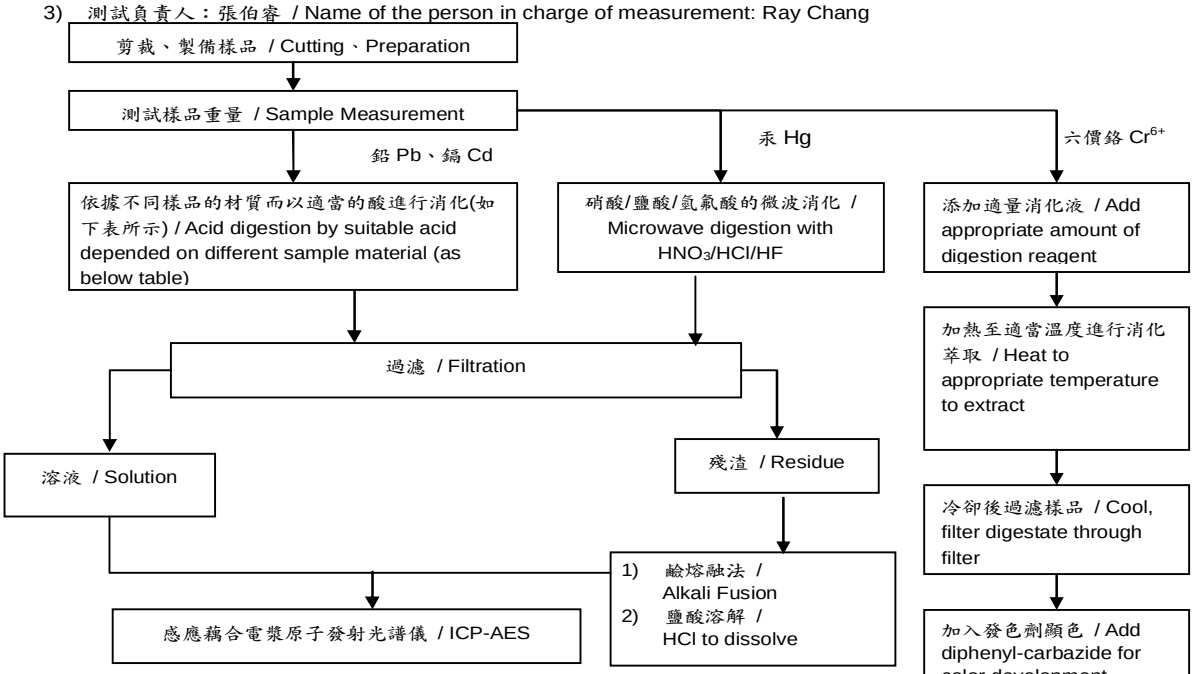
義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

德國產品安全委員會(AfPS) GS PAHs 要求 /
AfPS (German commission for Product Safety): GS PAHs requirements

項目 (Parameter)	第1類 (Category 1)	第2類 (Category 2)		第3類 (Category 3)	
	意圖放入嘴內的材料或玩具會與皮膚有所接觸(超過30秒). (Material indented to be put in the mouth or toys with intended skin contact (longer than 30 s).)	不屬於第1類的材料並可預見與皮膚接觸逾30秒(長期或經常與皮膚接觸). (Materials not falling under category 1 with foreseeable contact to skin for longer than 30 seconds (long-term skin or frequent contact).)		可預見與皮膚接觸短於30秒(短期與皮膚接觸), 以及不屬於第1類或第2類的材料. (Materials not falling under category 1 or 2 with foreseeable contact to skin for less than 30 seconds (short-term skin contact).)	
		列於2009/48/EC之玩具 (Toy under 2009/48/EC)	列於德國產品安全法之其他產品 (Other products under ProdSG)	列於2009/48/EC之玩具 (Toy under 2009/48/EC)	列於德國產品安全法之其他產品 (Other products under ProdSG)
Naphthalene	< 1	< 2		< 10	
Acenaphthylene Acenaphthene Fluorene Phenanthrene Anthracene Fluoranthene Pyrene	< 1 Sum	< 5 Sum	< 10 Sum	< 20 Sum	< 50 Sum
Benzo[a]anthracene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Chrysene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[b]fluoranthene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[j]fluoranthene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[k]fluoranthene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[a]pyrene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[e]pyrene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Indeno[1,2,3-c,d] pyrene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Dibenzo[a,h]anthracene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
Benzo[g,h,i]perylene	< 0.2	< 0.2	< 0.5	< 0.5	< 1
18項PAH總濃度 (Sum of 18 PAH)	< 1	< 5	< 10	< 20	< 50

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr^{6+} test method excluded)
2) 測試人員：劉俊宏 / Name of the person who made measurement: Jony Liu
3) 測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang



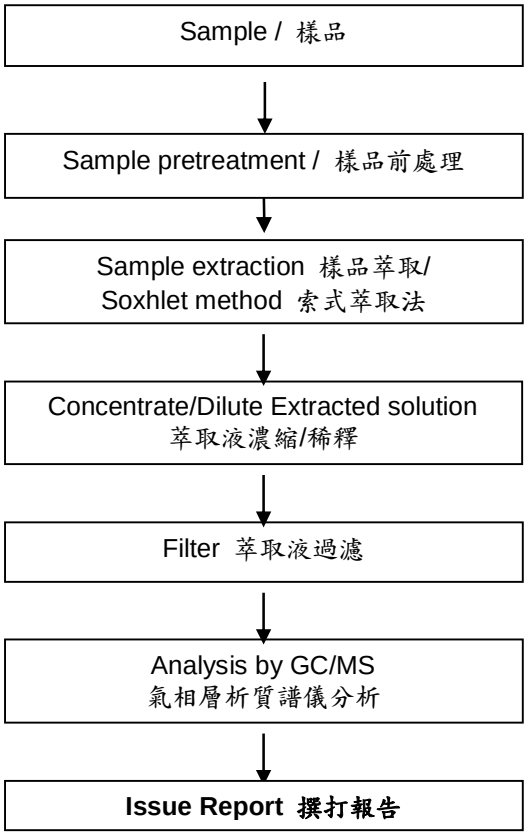
樣品材質 / Sample Material	消化酸液種類 / Digestion Acid
鋼, 銅, 鋁, 焊錫 / Steel, copper, aluminum, solder	王水, 硝酸, 鹽酸, 氫氟酸, 雙氧水 / Aqua regia, HNO_3, HCl, HF, H_2O_2
玻璃 / Glass	硝酸, 氫氟酸 / HNO_3/HF
金, 鉑, 鈀, 陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO_3
塑膠 / Plastic	硫酸, 雙氧水, 硝酸, 鹽酸 / H_2SO_4, H_2O_2, HNO_3, HCl
其他 / Others	加入任何酸至完全溶解 / Any acid to total digestion

Note：**(1) 針對非金屬材料加入鹼性消化液，加熱至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.
(2) 針對金屬材料加入純水，加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

多溴聯苯/多溴聯苯醚 分析流程圖 / PBB/PBDE analytical FLOW CHART

1)測試人員：陳威錚 / Name of the person who made measurement: Dorothy Chen
2)測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang

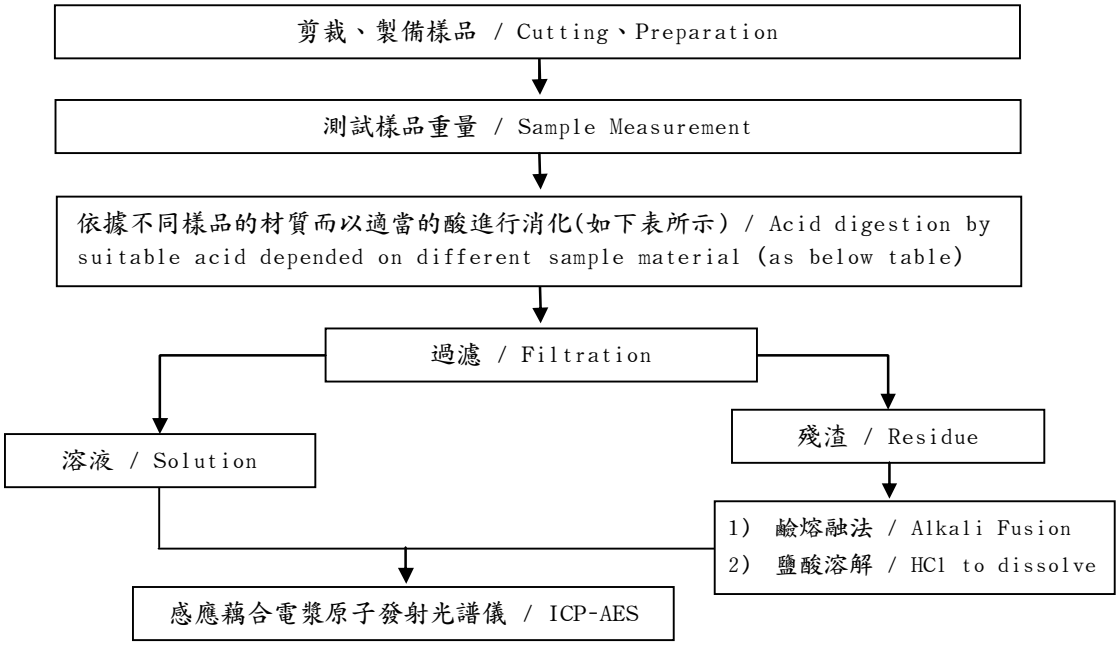


義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

1) 根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
2) 測試人員：劉俊宏 / Name of the person who made measurement: Jony Liu
3) 測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang

元素以 ICP-AES 分析的消化流程圖

(Flow Chart of digestion for the elements analysis performed by ICP-AES)



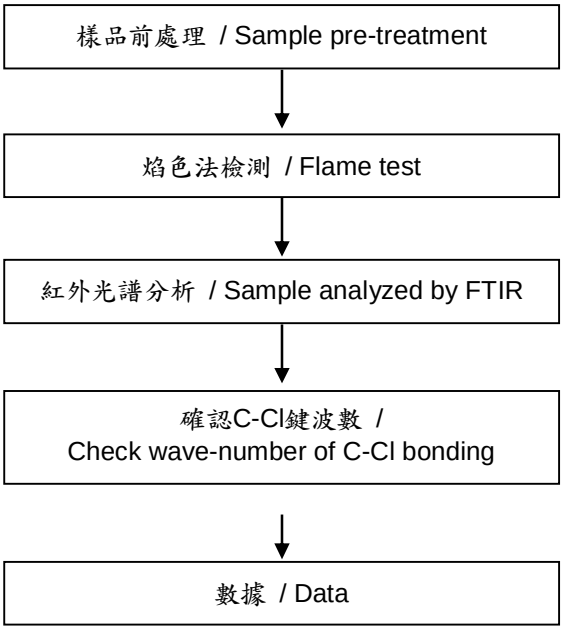
鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 / Aqua regia, HNO_3, HCl, HF, H_2O_2
玻璃 / Glass	硝酸,氫氟酸 / HNO_3/HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO_3
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H_2SO_4, H_2O_2, HNO_3, HCl
其他 / Others	加入任何酸至完全溶解 / Any acid to total digestion

義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

聚氯乙烯物質判定分析流程圖 /

Analysis flow chart for determination of PVC in material

1)測試人員：戴秀純 / Name of the person who made measurement: Hannah Tai
2)測試負責人：林立翔 / Name of the person in charge of measurement: Roger Lin

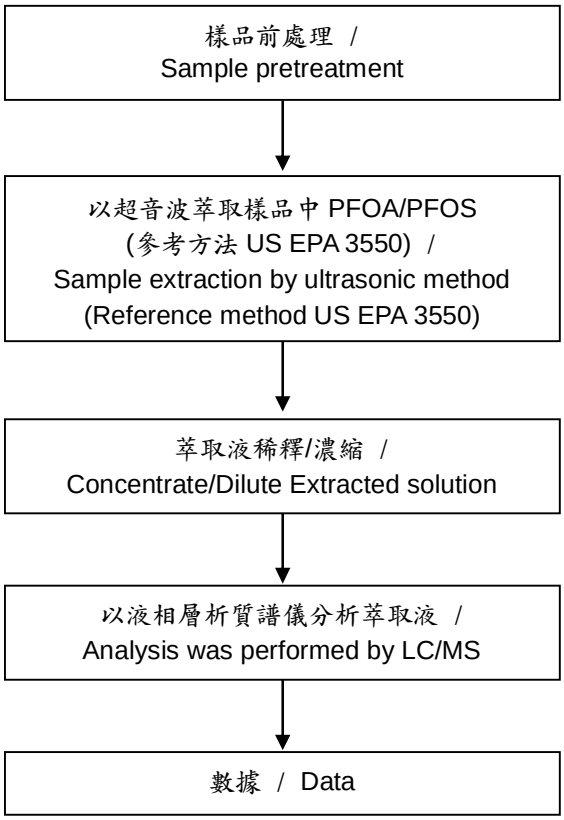


義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

全氟辛酸(鹽)/ 全氟辛烷磺酸分析流程圖 /
Analytical flow chart of PFOA/PFOS content

1)測試人員：黃璟瓔 / Name of the person who made measurement: Ginny Huang

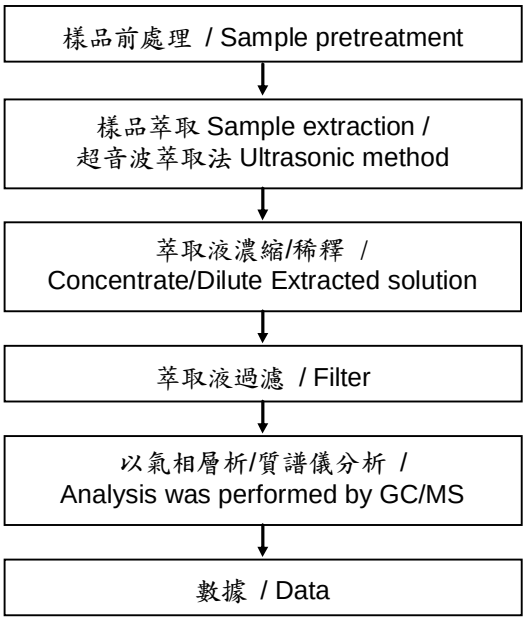
2)測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang



義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

六溴環十二烷分析流程圖 / HBCDD analytical flow chart

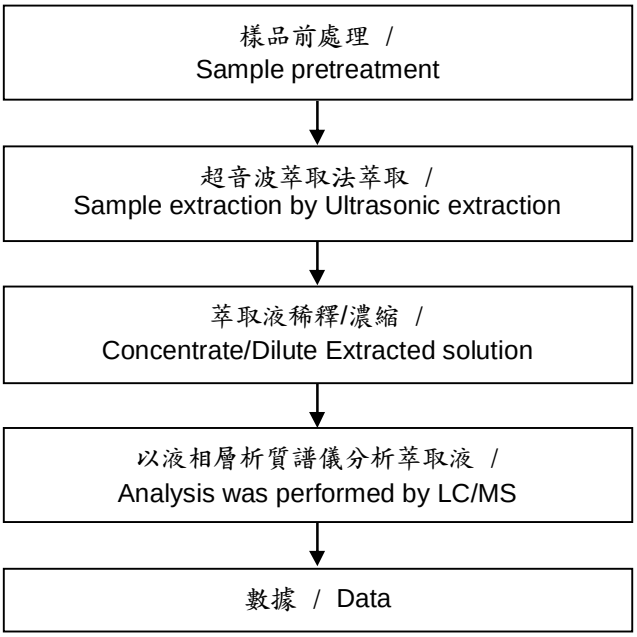
1) 測試人員：陳威錚/ Name of the person who made measurement: Dorothy Chen
2) 測試負責人：張伯睿/ Name of the person in charge of measurement: Ray Chang



義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

四溴雙酚-A分析流程圖 / TBBP-A analytical flow chart

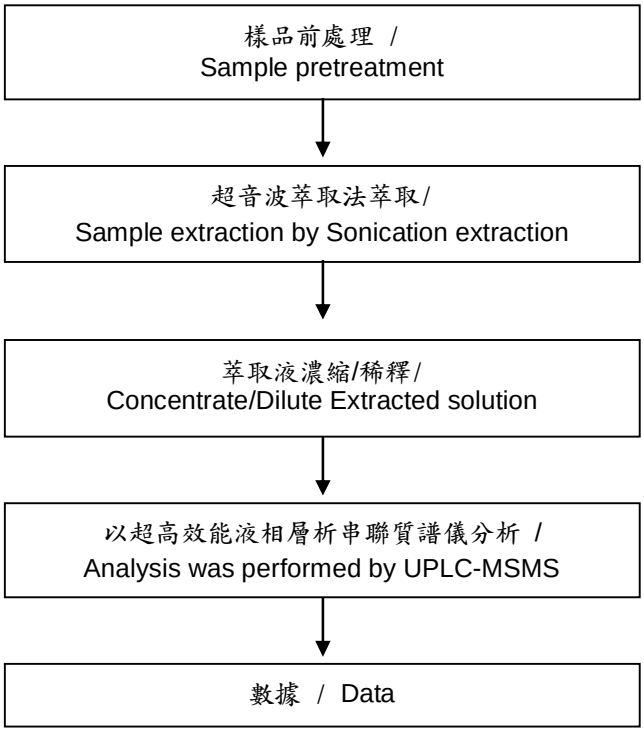
- 測試人員：黃璟瓔/ Name of the person who made measurement: Ginny Huang
- 測試負責人：張伯睿/ Name of the person in charge of measurement: Ray Chang



義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

雙酚A分析流程圖 / Bisphenol A analytical flow chart

- 測試人員：黃璟瓔 / Name of the person who made measurement: Ginny Huang
- 測試負責人：張伯睿/ Name of the person in charge of measurement: Ray Chang

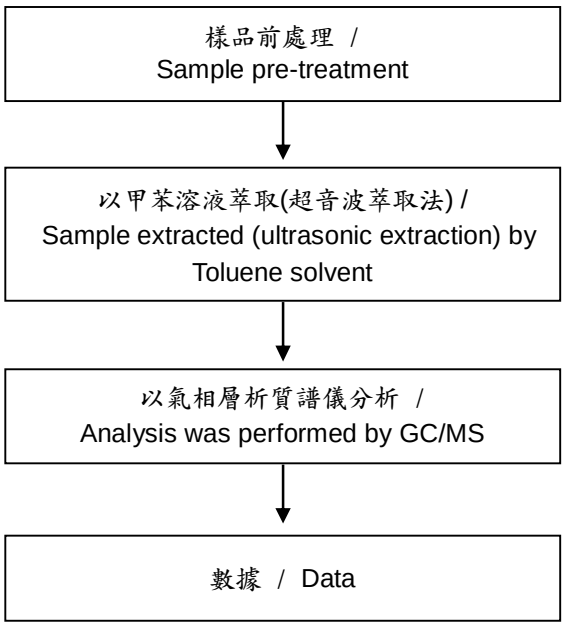


義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

多苯環芳香族化合物分析流程圖 /
PAHs (Poly Aromatic Hydrocarbons) analytical flow chart

1)測試人員：陳威錚 / Name of the person who made measurement: Dorothy Chen

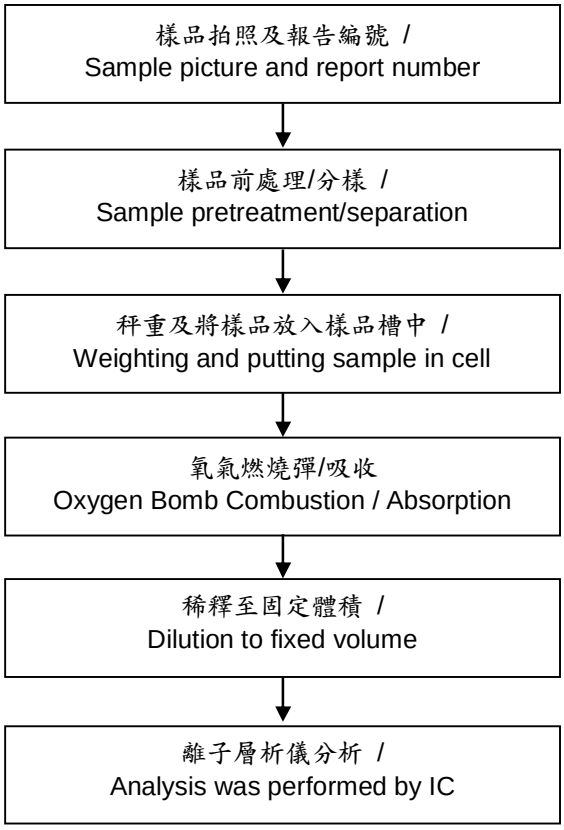
2)測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang



義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

鹵素分析流程圖 / Analytical flow chart of halogen content

1) 測試人員：洪秀眞/ Name of the person who made measurement: Jean Hung
2) 測試負責人：張伯睿/ Name of the person in charge of measurement: Ray Chang

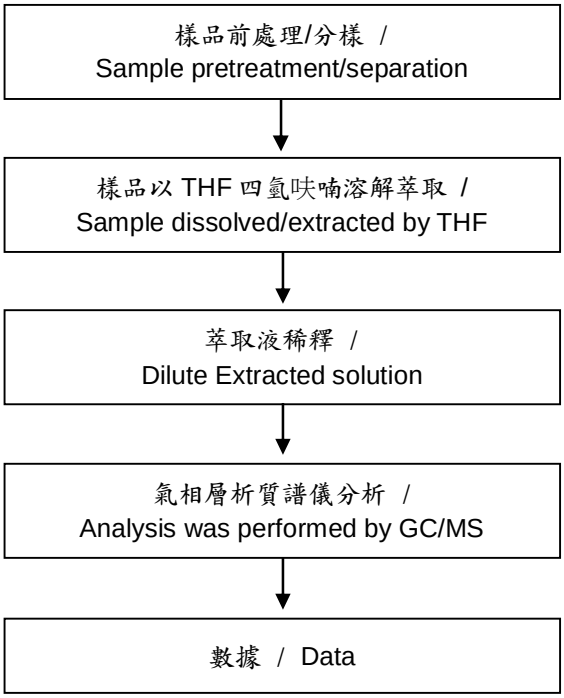


義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員：陳威錚 / Name of the person who made measurement: Dorothy Chen
- 測試負責人：張伯睿 / Name of the person in charge of measurement: Ray Chang

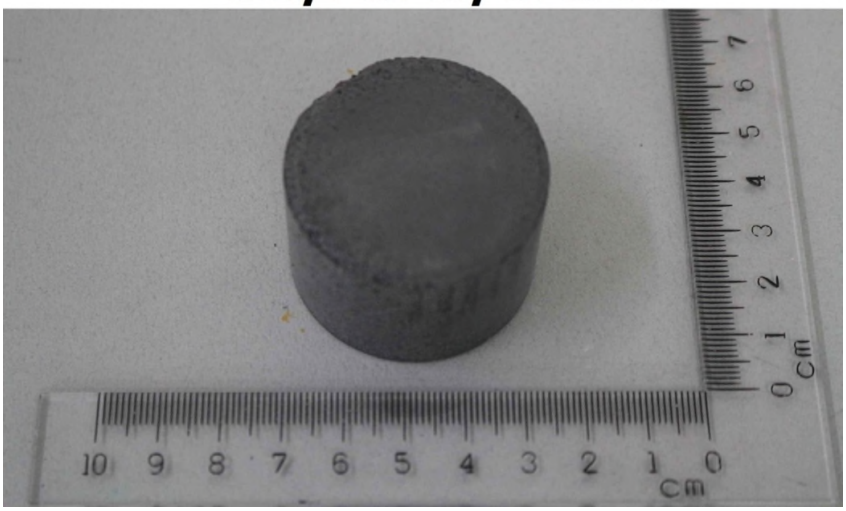
【測試方法/Test method: IEC 62321-8】



義典(無錫義典)科技股份有限公司
E'DALE(WUXI-E'DALE) TECHNOLOGY CO., LTD
72242 台南市佳里區六安里六安130號/江蘇省無錫市錫山區東港鎮錫港東路35號
NO. 130, LIOUAN, LIOUAN LI, JIALI DIST., TAINAN CITY, TAIWAN
NO. 35, XIGANG EAST ROAD, DONGGANG TOWN, XISHAN DIST., WUXI CITY, JIANG SU, CHINA

* 照片中如有箭頭標示，則表示爲實際檢測之樣品/部位. *
(The tested sample / part is marked by an arrow if it's shown on the photo.)

KA/2016/61540



** 報告結尾(End of Report) **

SeCoS Corporation

Reliability Testing Summary Report

Date: 2017/05/12 Document No.: SK17 -05- 102

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SSN3134K-C	150℃ ± 5℃, 80%VR, T = 1000 hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SSN3134K-C	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SSN3134K-C	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SSN3134K-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SSN3134K-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SSN3134K-C	85 ± 2℃, RH=85±5%, 80%VR, 1000 hrs		77	0	0	ACC
Resistance to Solder Heat Test	SSN3134K-C	270℃±5℃, 7Sec +2/-0Sec		77	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2017.03.20 Testing End Date: 2017.05.12

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃ ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	26.37V	0.035uA	315mΩ	26.01V	0.028uA	308mΩ
2	26.32V	0.019uA	314mΩ	26.02V	0.035uA	309mΩ
3	26.61V	0.018uA	313mΩ	26.76V	0.025uA	313mΩ
4	26.21V	0.025uA	314mΩ	26.20V	0.030uA	309mΩ
5	25.98V	0.034uA	312mΩ	26.96V	0.031uA	316mΩ
6	25.87V	0.018uA	310mΩ	26.20V	0.017uA	313mΩ
7	27.21V	0.024uA	315mΩ	27.22V	0.035uA	313mΩ
8	26.36V	0.020uA	313mΩ	26.62V	0.027uA	312mΩ
9	26.64V	0.029uA	310mΩ	26.16V	0.023uA	316mΩ
10	26.43V	0.036uA	314mΩ	26.63V	0.022uA	311mΩ
11	25.91V	0.033uA	313mΩ	25.96V	0.021uA	311mΩ
12	26.07V	0.028uA	315mΩ	27.00V	0.026uA	315mΩ
13	26.88V	0.017uA	315mΩ	26.40V	0.027uA	309mΩ
13	27.26V	0.024uA	310mΩ	27.21V	0.031uA	313mΩ
15	26.09V	0.023uA	312mΩ	26.02V	0.036uA	316mΩ
16	26.88V	0.026uA	308mΩ	26.72V	0.029uA	316mΩ
17	27.21V	0.018uA	312mΩ	26.39V	0.036uA	312mΩ
18	25.94V	0.023uA	315mΩ	26.37V	0.029uA	310mΩ
19	26.40V	0.031uA	308mΩ	26.89V	0.033uA	310mΩ
20	26.69V	0.035uA	316mΩ	27.18V	0.037uA	309mΩ
21	26.71V	0.028uA	313mΩ	25.89V	0.035uA	315mΩ
22	26.88V	0.032uA	317mΩ	26.84V	0.036uA	311mΩ
23	26.58V	0.033uA	309mΩ	25.93V	0.025uA	313mΩ
24	25.93V	0.033uA	311mΩ	26.53V	0.026uA	311mΩ
25	27.16V	0.021uA	315mΩ	26.94V	0.034uA	309mΩ
26	26.22V	0.035uA	316mΩ	26.45V	0.027uA	310mΩ
27	26.88V	0.028uA	316mΩ	26.15V	0.021uA	309mΩ
28	26.67V	0.035uA	315mΩ	26.08V	0.035uA	317mΩ
29	26.36V	0.018uA	316mΩ	26.90V	0.029uA	312mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃ ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	27.27V	0.026uA	311mΩ	25.98V	0.034uA	316mΩ
31	26.35V	0.024uA	312mΩ	26.41V	0.035uA	311mΩ
32	26.37V	0.020uA	314mΩ	26.77V	0.031uA	316mΩ
33	26.49V	0.019uA	311mΩ	26.77V	0.018uA	311mΩ
34	26.66V	0.027uA	314mΩ	25.89V	0.017uA	315mΩ
35	27.03V	0.027uA	316mΩ	26.58V	0.031uA	311mΩ
36	26.26V	0.025uA	312mΩ	27.05V	0.032uA	314mΩ
37	26.13V	0.023uA	316mΩ	26.50V	0.027uA	311mΩ
38	26.09V	0.030uA	315mΩ	27.03V	0.029uA	310mΩ
39	26.88V	0.031uA	313mΩ	25.98V	0.018uA	317mΩ
40	26.45V	0.032uA	313mΩ	25.88V	0.025uA	316mΩ
41	26.54V	0.032uA	313mΩ	26.92V	0.031uA	313mΩ
42	27.15V	0.021uA	309mΩ	26.06V	0.032uA	314mΩ
43	25.94V	0.022uA	310mΩ	26.94V	0.032uA	309mΩ
44	27.03V	0.022uA	310mΩ	26.28V	0.021uA	314mΩ
45	26.95V	0.034uA	313mΩ	27.16V	0.029uA	309mΩ
46	27.16V	0.031uA	310mΩ	27.22V	0.017uA	311mΩ
47	26.65V	0.037uA	310mΩ	26.04V	0.033uA	313mΩ
48	26.79V	0.024uA	308mΩ	26.71V	0.022uA	308mΩ
49	26.59V	0.037uA	315mΩ	26.34V	0.036uA	311mΩ
50	27.20V	0.020uA	315mΩ	26.45V	0.021uA	311mΩ
51	26.20V	0.018uA	311mΩ	26.70V	0.022uA	313mΩ
52	26.03V	0.026uA	315mΩ	26.15V	0.031uA	313mΩ
53	25.94V	0.033uA	313mΩ	26.58V	0.033uA	317mΩ
54	26.38V	0.029uA	314mΩ	26.48V	0.019uA	310mΩ
55	26.12V	0.019uA	311mΩ	26.14V	0.027uA	313mΩ
56	27.25V	0.025uA	315mΩ	26.40V	0.022uA	311mΩ
57	27.05V	0.033uA	308mΩ	26.26V	0.031uA	315mΩ
58	26.78V	0.033uA	310mΩ	26.23V	0.018uA	316mΩ

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃ ± 5℃, 80%VR, T = 1000 hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A108
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	26.17V	0.028uA	314mΩ	26.51V	0.029uA	311mΩ
60	26.27V	0.019uA	314mΩ	26.85V	0.024uA	308mΩ
61	26.65V	0.035uA	308mΩ	26.01V	0.029uA	315mΩ
62	26.63V	0.028uA	309mΩ	26.00V	0.023uA	315mΩ
63	26.44V	0.029uA	312mΩ	26.53V	0.023uA	312mΩ
64	27.16V	0.031uA	314mΩ	26.45V	0.031uA	308mΩ
65	26.12V	0.019uA	308mΩ	26.40V	0.036uA	315mΩ
66	27.10V	0.030uA	315mΩ	26.97V	0.022uA	315mΩ
67	26.99V	0.031uA	309mΩ	26.09V	0.033uA	315mΩ
68	27.03V	0.022uA	312mΩ	26.72V	0.032uA	313mΩ
69	27.24V	0.029uA	314mΩ	26.84V	0.023uA	314mΩ
70	26.68V	0.026uA	313mΩ	26.93V	0.028uA	315mΩ
71	26.31V	0.020uA	313mΩ	27.19V	0.036uA	315mΩ
72	26.79V	0.031uA	313mΩ	27.01V	0.028uA	314mΩ
73	25.93V	0.029uA	311mΩ	26.46V	0.021uA	310mΩ
74	26.65V	0.017uA	309mΩ	26.07V	0.022uA	312mΩ
75	26.60V	0.020uA	313mΩ	26.92V	0.025uA	317mΩ
76	26.07V	0.033uA	313mΩ	26.70V	0.035uA	312mΩ
77	25.93V	0.029uA	309mΩ	26.50V	0.024uA	313mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃, 1000Hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	25.90V	0.032uA	312mΩ	26.06V	0.021uA	316mΩ
2	26.17V	0.026uA	316mΩ	26.85V	0.028uA	309mΩ
3	26.80V	0.025uA	313mΩ	27.04V	0.037uA	313mΩ
4	26.20V	0.036uA	316mΩ	27.22V	0.027uA	314mΩ
5	26.73V	0.024uA	317mΩ	26.12V	0.032uA	310mΩ
6	26.49V	0.029uA	313mΩ	25.92V	0.031uA	315mΩ
7	26.90V	0.028uA	312mΩ	26.85V	0.019uA	310mΩ
8	26.30V	0.025uA	313mΩ	26.51V	0.032uA	313mΩ
9	27.25V	0.017uA	316mΩ	26.84V	0.032uA	312mΩ
10	26.40V	0.018uA	311mΩ	26.29V	0.030uA	310mΩ
11	25.94V	0.027uA	312mΩ	26.97V	0.022uA	311mΩ
12	26.87V	0.019uA	309mΩ	27.01V	0.024uA	308mΩ
13	26.33V	0.029uA	314mΩ	27.27V	0.027uA	309mΩ
13	27.16V	0.029uA	316mΩ	26.02V	0.027uA	313mΩ
15	26.07V	0.018uA	309mΩ	26.28V	0.025uA	315mΩ
16	26.35V	0.028uA	311mΩ	26.50V	0.020uA	310mΩ
17	26.59V	0.023uA	312mΩ	27.18V	0.031uA	310mΩ
18	26.23V	0.027uA	316mΩ	26.56V	0.025uA	314mΩ
19	26.40V	0.021uA	312mΩ	27.23V	0.025uA	309mΩ
20	26.40V	0.023uA	316mΩ	26.93V	0.022uA	310mΩ
21	26.31V	0.026uA	315mΩ	26.08V	0.034uA	311mΩ
22	26.70V	0.024uA	312mΩ	26.89V	0.021uA	314mΩ
23	27.15V	0.020uA	309mΩ	26.64V	0.019uA	309mΩ
24	26.84V	0.018uA	312mΩ	26.13V	0.035uA	308mΩ
25	27.04V	0.029uA	309mΩ	26.32V	0.032uA	313mΩ
26	25.88V	0.035uA	317mΩ	26.08V	0.031uA	314mΩ
27	26.90V	0.022uA	312mΩ	26.46V	0.031uA	311mΩ
28	26.16V	0.030uA	317mΩ	26.81V	0.033uA	309mΩ
29	26.12V	0.037uA	309mΩ	26.99V	0.032uA	315mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃, 1000Hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	26.67V	0.036uA	309mΩ	26.89V	0.035uA	317mΩ
31	27.00V	0.030uA	311mΩ	26.32V	0.023uA	310mΩ
32	26.12V	0.028uA	311mΩ	26.62V	0.028uA	314mΩ
33	26.64V	0.026uA	315mΩ	26.84V	0.025uA	310mΩ
34	26.14V	0.033uA	310mΩ	26.99V	0.030uA	312mΩ
35	27.18V	0.035uA	308mΩ	26.25V	0.037uA	314mΩ
36	26.97V	0.026uA	317mΩ	26.94V	0.027uA	311mΩ
37	26.24V	0.034uA	309mΩ	26.17V	0.024uA	313mΩ
38	26.59V	0.033uA	310mΩ	26.61V	0.029uA	311mΩ
39	26.13V	0.027uA	309mΩ	26.29V	0.018uA	309mΩ
40	25.93V	0.023uA	311mΩ	27.27V	0.020uA	308mΩ
41	26.91V	0.018uA	313mΩ	26.13V	0.034uA	309mΩ
42	26.72V	0.028uA	314mΩ	26.88V	0.024uA	308mΩ
43	27.02V	0.036uA	315mΩ	26.46V	0.029uA	310mΩ
44	26.91V	0.020uA	310mΩ	26.01V	0.029uA	315mΩ
45	26.54V	0.033uA	314mΩ	27.22V	0.031uA	312mΩ
46	27.04V	0.036uA	316mΩ	26.85V	0.032uA	311mΩ
47	26.42V	0.026uA	315mΩ	26.71V	0.035uA	314mΩ
48	26.53V	0.018uA	309mΩ	25.99V	0.026uA	316mΩ
49	26.30V	0.033uA	309mΩ	26.75V	0.025uA	313mΩ
50	25.91V	0.030uA	310mΩ	27.07V	0.020uA	310mΩ
51	26.50V	0.021uA	309mΩ	27.17V	0.025uA	311mΩ
52	27.09V	0.035uA	311mΩ	26.96V	0.033uA	314mΩ
53	26.92V	0.028uA	312mΩ	26.78V	0.028uA	312mΩ
54	25.99V	0.021uA	311mΩ	26.62V	0.023uA	317mΩ
55	26.74V	0.020uA	309mΩ	26.70V	0.025uA	312mΩ
56	26.13V	0.024uA	315mΩ	26.67V	0.028uA	314mΩ
57	26.04V	0.033uA	308mΩ	26.48V	0.032uA	312mΩ
58	26.38V	0.037uA	317mΩ	26.93V	0.019uA	311mΩ

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 150℃, 1000Hrs
Test Date: 2017.03.20 ~ 2017.05.02
Test Standard : JESD22 STANDARD Method-A103
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	27.21V	0.031uA	310mΩ	26.83V	0.034uA	315mΩ
60	26.74V	0.029uA	310mΩ	26.75V	0.024uA	312mΩ
61	27.03V	0.035uA	309mΩ	26.33V	0.032uA	311mΩ
62	26.15V	0.019uA	310mΩ	26.70V	0.036uA	308mΩ
63	26.07V	0.027uA	315mΩ	27.17V	0.021uA	309mΩ
64	27.03V	0.033uA	309mΩ	26.43V	0.020uA	313mΩ
65	26.81V	0.024uA	310mΩ	26.41V	0.018uA	309mΩ
66	26.24V	0.029uA	312mΩ	26.64V	0.025uA	313mΩ
67	26.20V	0.036uA	309mΩ	26.70V	0.035uA	309mΩ
68	26.06V	0.023uA	310mΩ	26.27V	0.027uA	314mΩ
69	26.29V	0.030uA	317mΩ	26.25V	0.036uA	316mΩ
70	26.02V	0.036uA	309mΩ	27.03V	0.023uA	316mΩ
71	26.01V	0.033uA	310mΩ	26.94V	0.035uA	315mΩ
72	26.29V	0.025uA	311mΩ	26.73V	0.024uA	317mΩ
73	27.08V	0.023uA	309mΩ	27.23V	0.026uA	310mΩ
74	26.77V	0.021uA	317mΩ	27.03V	0.024uA	309mΩ
75	26.92V	0.030uA	312mΩ	26.93V	0.034uA	308mΩ
76	27.01V	0.020uA	312mΩ	27.26V	0.024uA	308mΩ
77	26.87V	0.031uA	316mΩ	26.23V	0.032uA	312mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2017.03.20 ~ 2017.03.28
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	25.98V	0.034uA	311mΩ	26.83V	0.027uA	310mΩ
2	26.95V	0.027uA	309mΩ	26.84V	0.037uA	309mΩ
3	26.43V	0.027uA	315mΩ	26.90V	0.030uA	312mΩ
4	25.99V	0.030uA	312mΩ	27.22V	0.019uA	309mΩ
5	26.23V	0.028uA	314mΩ	26.77V	0.035uA	309mΩ
6	26.55V	0.033uA	315mΩ	26.69V	0.025uA	313mΩ
7	27.18V	0.023uA	309mΩ	26.39V	0.033uA	313mΩ
8	26.12V	0.019uA	312mΩ	26.83V	0.018uA	312mΩ
9	25.96V	0.026uA	316mΩ	26.28V	0.037uA	314mΩ
10	26.70V	0.032uA	316mΩ	26.05V	0.032uA	315mΩ
11	26.77V	0.025uA	310mΩ	26.67V	0.033uA	313mΩ
12	26.91V	0.025uA	316mΩ	26.10V	0.036uA	308mΩ
13	26.66V	0.018uA	315mΩ	27.00V	0.029uA	309mΩ
13	26.98V	0.025uA	310mΩ	27.18V	0.018uA	309mΩ
15	27.19V	0.021uA	311mΩ	25.94V	0.018uA	311mΩ
16	26.58V	0.028uA	314mΩ	25.91V	0.036uA	317mΩ
17	26.35V	0.027uA	309mΩ	26.51V	0.018uA	310mΩ
18	26.41V	0.033uA	315mΩ	26.16V	0.023uA	313mΩ
19	26.73V	0.037uA	314mΩ	25.89V	0.037uA	312mΩ
20	26.66V	0.024uA	314mΩ	26.75V	0.023uA	313mΩ
21	26.06V	0.034uA	309mΩ	26.07V	0.025uA	313mΩ
22	26.81V	0.036uA	316mΩ	27.11V	0.023uA	316mΩ
23	26.28V	0.031uA	315mΩ	27.00V	0.026uA	311mΩ
24	26.74V	0.035uA	310mΩ	27.08V	0.028uA	309mΩ
25	27.06V	0.019uA	317mΩ	27.12V	0.028uA	316mΩ
26	26.35V	0.019uA	312mΩ	26.26V	0.031uA	317mΩ
27	27.06V	0.024uA	313mΩ	26.04V	0.028uA	312mΩ
28	25.92V	0.029uA	311mΩ	26.01V	0.019uA	315mΩ
29	26.64V	0.027uA	314mΩ	27.04V	0.029uA	317mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2017.03.20 ~ 2017.03.28
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	27.15V	0.023uA	310mΩ	26.42V	0.028uA	312mΩ
31	26.55V	0.023uA	312mΩ	26.69V	0.018uA	316mΩ
32	26.34V	0.034uA	315mΩ	26.69V	0.032uA	315mΩ
33	26.47V	0.019uA	309mΩ	26.57V	0.022uA	315mΩ
34	25.91V	0.035uA	312mΩ	26.69V	0.026uA	313mΩ
35	26.10V	0.031uA	311mΩ	25.89V	0.035uA	313mΩ
36	26.01V	0.022uA	312mΩ	26.82V	0.022uA	311mΩ
37	27.10V	0.019uA	309mΩ	26.28V	0.028uA	314mΩ
38	26.39V	0.036uA	316mΩ	26.35V	0.022uA	310mΩ
39	26.95V	0.024uA	310mΩ	25.89V	0.029uA	312mΩ
40	26.93V	0.024uA	316mΩ	26.20V	0.019uA	317mΩ
41	25.95V	0.033uA	316mΩ	26.67V	0.034uA	309mΩ
42	26.76V	0.024uA	317mΩ	26.45V	0.029uA	314mΩ
43	26.84V	0.031uA	316mΩ	26.63V	0.031uA	309mΩ
44	26.70V	0.029uA	310mΩ	27.19V	0.017uA	311mΩ
45	26.26V	0.026uA	315mΩ	26.12V	0.034uA	308mΩ
46	27.11V	0.030uA	311mΩ	26.30V	0.030uA	312mΩ
47	26.41V	0.027uA	316mΩ	26.72V	0.030uA	312mΩ
48	26.48V	0.020uA	313mΩ	27.10V	0.035uA	309mΩ
49	26.72V	0.037uA	309mΩ	26.14V	0.031uA	312mΩ
50	26.51V	0.021uA	310mΩ	26.92V	0.019uA	310mΩ
51	27.10V	0.034uA	313mΩ	27.05V	0.031uA	309mΩ
52	25.95V	0.019uA	316mΩ	26.84V	0.036uA	308mΩ
53	26.64V	0.028uA	313mΩ	26.21V	0.035uA	316mΩ
54	25.92V	0.029uA	314mΩ	25.90V	0.026uA	312mΩ
55	26.88V	0.029uA	311mΩ	25.97V	0.037uA	309mΩ
56	26.39V	0.027uA	314mΩ	25.96V	0.025uA	309mΩ
57	27.10V	0.021uA	317mΩ	27.01V	0.031uA	309mΩ
58	27.11V	0.020uA	308mΩ	26.75V	0.026uA	312mΩ

SeCoS Corporation

Pressure Cooker Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs
Test Date: 2017.03.20 ~ 2017.03.28
Test Standard : JESD22 STANDARD Method-A102
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	25.92V	0.032uA	316mΩ	25.92V	0.030uA	309mΩ
60	26.86V	0.025uA	316mΩ	26.05V	0.020uA	316mΩ
61	26.75V	0.026uA	313mΩ	26.35V	0.028uA	311mΩ
62	25.97V	0.036uA	310mΩ	26.41V	0.033uA	308mΩ
63	26.87V	0.035uA	309mΩ	26.98V	0.029uA	308mΩ
64	26.74V	0.020uA	313mΩ	26.31V	0.019uA	310mΩ
65	27.20V	0.017uA	312mΩ	26.25V	0.021uA	313mΩ
66	26.07V	0.029uA	314mΩ	26.63V	0.035uA	310mΩ
67	26.49V	0.028uA	311mΩ	26.97V	0.034uA	317mΩ
68	26.87V	0.032uA	316mΩ	26.78V	0.037uA	310mΩ
69	26.50V	0.022uA	309mΩ	26.97V	0.029uA	314mΩ
70	26.90V	0.036uA	311mΩ	26.54V	0.019uA	311mΩ
71	27.11V	0.024uA	315mΩ	25.99V	0.032uA	311mΩ
72	26.27V	0.021uA	308mΩ	26.47V	0.027uA	311mΩ
73	26.09V	0.033uA	312mΩ	26.73V	0.026uA	309mΩ
74	26.93V	0.018uA	313mΩ	26.22V	0.023uA	314mΩ
75	27.24V	0.021uA	317mΩ	26.91V	0.032uA	309mΩ
76	26.76V	0.032uA	316mΩ	26.12V	0.019uA	311mΩ
77	27.17V	0.020uA	311mΩ	26.30V	0.035uA	314mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2017.03.21 ~ 2017.05.12
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	26.45V	0.021uA	312mΩ	26.27V	0.037uA	310mΩ
2	26.73V	0.037uA	311mΩ	26.11V	0.036uA	317mΩ
3	26.32V	0.025uA	310mΩ	26.31V	0.019uA	308mΩ
4	25.87V	0.028uA	316mΩ	26.32V	0.030uA	316mΩ
5	27.15V	0.019uA	309mΩ	26.84V	0.033uA	313mΩ
6	26.51V	0.024uA	312mΩ	25.91V	0.023uA	314mΩ
7	26.49V	0.019uA	313mΩ	26.53V	0.021uA	312mΩ
8	27.10V	0.025uA	315mΩ	26.56V	0.024uA	312mΩ
9	27.03V	0.028uA	309mΩ	26.74V	0.034uA	310mΩ
10	26.84V	0.035uA	317mΩ	26.56V	0.036uA	311mΩ
11	26.84V	0.031uA	314mΩ	25.95V	0.035uA	314mΩ
12	27.10V	0.023uA	312mΩ	26.24V	0.034uA	313mΩ
13	26.70V	0.036uA	314mΩ	26.29V	0.030uA	313mΩ
13	25.90V	0.034uA	311mΩ	26.13V	0.037uA	309mΩ
15	26.11V	0.024uA	315mΩ	26.94V	0.037uA	312mΩ
16	26.69V	0.035uA	311mΩ	26.30V	0.018uA	316mΩ
17	26.20V	0.037uA	309mΩ	25.97V	0.022uA	313mΩ
18	26.42V	0.024uA	313mΩ	26.50V	0.021uA	312mΩ
19	25.98V	0.029uA	314mΩ	26.85V	0.030uA	312mΩ
20	26.87V	0.022uA	312mΩ	26.78V	0.031uA	313mΩ
21	26.92V	0.027uA	313mΩ	26.93V	0.030uA	309mΩ
22	26.18V	0.026uA	315mΩ	26.15V	0.033uA	311mΩ
23	26.77V	0.025uA	311mΩ	26.11V	0.018uA	315mΩ
24	26.61V	0.021uA	317mΩ	26.53V	0.034uA	311mΩ
25	26.12V	0.034uA	312mΩ	26.71V	0.027uA	316mΩ
26	27.15V	0.019uA	310mΩ	26.99V	0.030uA	311mΩ
27	26.58V	0.020uA	311mΩ	26.89V	0.033uA	310mΩ
28	26.27V	0.035uA	315mΩ	25.92V	0.024uA	311mΩ
29	27.08V	0.035uA	310mΩ	27.23V	0.019uA	312mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2017.03.21 ~ 2017.05.12
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	27.05V	0.025uA	308mΩ	26.90V	0.023uA	317mΩ
31	26.18V	0.036uA	310mΩ	26.59V	0.022uA	316mΩ
32	26.33V	0.022uA	315mΩ	26.31V	0.034uA	314mΩ
33	26.52V	0.027uA	317mΩ	26.04V	0.035uA	314mΩ
34	26.54V	0.027uA	311mΩ	26.93V	0.026uA	317mΩ
35	26.34V	0.026uA	311mΩ	25.95V	0.034uA	316mΩ
36	26.68V	0.034uA	309mΩ	25.95V	0.022uA	311mΩ
37	25.95V	0.034uA	314mΩ	26.97V	0.032uA	313mΩ
38	25.95V	0.023uA	310mΩ	26.05V	0.033uA	313mΩ
39	26.66V	0.033uA	316mΩ	26.10V	0.023uA	315mΩ
40	26.16V	0.036uA	314mΩ	25.98V	0.021uA	310mΩ
41	25.90V	0.025uA	314mΩ	26.98V	0.033uA	314mΩ
42	27.11V	0.036uA	315mΩ	26.53V	0.030uA	313mΩ
43	27.10V	0.022uA	316mΩ	26.78V	0.029uA	310mΩ
44	25.92V	0.037uA	309mΩ	26.48V	0.027uA	311mΩ
45	26.31V	0.035uA	312mΩ	27.00V	0.022uA	311mΩ
46	26.56V	0.018uA	313mΩ	26.17V	0.027uA	308mΩ
47	26.93V	0.022uA	309mΩ	27.20V	0.031uA	310mΩ
48	26.12V	0.022uA	317mΩ	26.32V	0.028uA	313mΩ
49	26.00V	0.036uA	314mΩ	25.92V	0.034uA	309mΩ
50	26.33V	0.034uA	311mΩ	26.51V	0.030uA	309mΩ
51	26.50V	0.030uA	314mΩ	26.45V	0.020uA	308mΩ
52	26.90V	0.030uA	316mΩ	26.01V	0.025uA	316mΩ
53	26.26V	0.026uA	308mΩ	25.89V	0.034uA	310mΩ
54	27.22V	0.035uA	315mΩ	26.29V	0.022uA	311mΩ
55	26.13V	0.020uA	312mΩ	26.54V	0.019uA	308mΩ
56	26.93V	0.030uA	312mΩ	26.38V	0.030uA	314mΩ
57	26.83V	0.033uA	313mΩ	27.16V	0.032uA	316mΩ
58	26.41V	0.019uA	310mΩ	26.37V	0.021uA	314mΩ

SeCoS Corporation

Temperature Cycle Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle
Test Date: 2017.03.21 ~ 2017.05.12
Test Standard : JESD22 STANDARD Method-A104
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	27.22V	0.020uA	314mΩ	26.52V	0.028uA	309mΩ
60	26.66V	0.028uA	313mΩ	27.07V	0.022uA	310mΩ
61	26.49V	0.028uA	311mΩ	26.51V	0.027uA	312mΩ
62	26.84V	0.024uA	314mΩ	27.09V	0.023uA	311mΩ
63	26.05V	0.025uA	310mΩ	26.71V	0.020uA	311mΩ
64	26.14V	0.019uA	309mΩ	27.05V	0.022uA	310mΩ
65	27.23V	0.018uA	311mΩ	26.98V	0.023uA	312mΩ
66	26.34V	0.033uA	313mΩ	26.77V	0.021uA	312mΩ
67	26.43V	0.031uA	311mΩ	27.01V	0.024uA	316mΩ
68	26.75V	0.027uA	316mΩ	25.89V	0.018uA	311mΩ
69	25.97V	0.023uA	314mΩ	27.16V	0.029uA	314mΩ
70	26.71V	0.024uA	317mΩ	26.40V	0.020uA	316mΩ
71	26.25V	0.021uA	316mΩ	26.83V	0.030uA	316mΩ
72	26.99V	0.019uA	312mΩ	25.98V	0.030uA	313mΩ
73	26.47V	0.034uA	313mΩ	26.23V	0.032uA	309mΩ
74	26.26V	0.031uA	312mΩ	27.05V	0.022uA	317mΩ
75	26.55V	0.033uA	311mΩ	27.16V	0.036uA	314mΩ
76	26.91V	0.022uA	313mΩ	26.59V	0.035uA	310mΩ
77	26.34V	0.025uA	315mΩ	26.68V	0.018uA	313mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	26.55V	0.030uA	313mΩ	26.58V	0.024uA	313mΩ
2	26.43V	0.032uA	310mΩ	26.97V	0.019uA	310mΩ
3	26.11V	0.018uA	313mΩ	27.12V	0.029uA	311mΩ
4	26.47V	0.030uA	311mΩ	26.45V	0.020uA	315mΩ
5	27.25V	0.019uA	309mΩ	26.74V	0.022uA	315mΩ
6	26.18V	0.036uA	315mΩ	26.83V	0.026uA	314mΩ
7	25.97V	0.017uA	311mΩ	26.93V	0.022uA	311mΩ
8	26.36V	0.034uA	315mΩ	26.60V	0.034uA	317mΩ
9	26.22V	0.035uA	314mΩ	27.21V	0.035uA	313mΩ
10	26.91V	0.032uA	308mΩ	27.15V	0.020uA	312mΩ
11	27.22V	0.019uA	315mΩ	26.70V	0.036uA	316mΩ
12	27.06V	0.023uA	313mΩ	26.41V	0.019uA	312mΩ
13	26.64V	0.032uA	312mΩ	26.36V	0.029uA	314mΩ
13	26.19V	0.032uA	314mΩ	26.79V	0.033uA	308mΩ
15	26.88V	0.031uA	311mΩ	26.02V	0.034uA	314mΩ
16	26.82V	0.032uA	315mΩ	26.59V	0.025uA	313mΩ
17	26.82V	0.028uA	313mΩ	26.41V	0.020uA	314mΩ
18	26.84V	0.027uA	314mΩ	26.03V	0.036uA	309mΩ
19	26.48V	0.027uA	312mΩ	26.93V	0.032uA	309mΩ
20	26.20V	0.029uA	309mΩ	26.85V	0.028uA	313mΩ
21	26.94V	0.023uA	314mΩ	26.95V	0.023uA	314mΩ
22	25.87V	0.036uA	310mΩ	26.85V	0.034uA	308mΩ
23	26.14V	0.026uA	313mΩ	26.45V	0.017uA	309mΩ
24	26.25V	0.017uA	311mΩ	27.00V	0.032uA	310mΩ
25	26.12V	0.024uA	314mΩ	26.87V	0.024uA	309mΩ
26	26.06V	0.030uA	312mΩ	26.27V	0.017uA	309mΩ
27	26.98V	0.029uA	315mΩ	26.08V	0.033uA	311mΩ
28	25.98V	0.033uA	311mΩ	25.94V	0.034uA	314mΩ
29	26.31V	0.031uA	311mΩ	26.69V	0.027uA	311mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	27.25V	0.032uA	314mΩ	26.54V	0.024uA	311mΩ
31	26.01V	0.035uA	316mΩ	26.85V	0.029uA	308mΩ
32	27.21V	0.036uA	312mΩ	27.18V	0.032uA	309mΩ
33	25.95V	0.030uA	315mΩ	25.89V	0.021uA	309mΩ
34	27.09V	0.019uA	310mΩ	26.67V	0.019uA	312mΩ
35	26.61V	0.033uA	315mΩ	26.02V	0.022uA	313mΩ
36	26.76V	0.028uA	311mΩ	26.95V	0.028uA	312mΩ
37	26.07V	0.027uA	316mΩ	26.75V	0.021uA	310mΩ
38	27.10V	0.032uA	316mΩ	26.35V	0.020uA	313mΩ
39	27.20V	0.031uA	311mΩ	26.41V	0.031uA	310mΩ
40	26.20V	0.022uA	316mΩ	26.84V	0.032uA	314mΩ
41	26.61V	0.026uA	308mΩ	26.90V	0.024uA	309mΩ
42	26.09V	0.037uA	314mΩ	26.44V	0.018uA	312mΩ
43	26.29V	0.026uA	310mΩ	26.51V	0.019uA	309mΩ
44	27.11V	0.028uA	310mΩ	26.90V	0.017uA	310mΩ
45	26.61V	0.024uA	313mΩ	26.71V	0.018uA	312mΩ
46	26.70V	0.020uA	311mΩ	27.15V	0.023uA	317mΩ
47	27.12V	0.018uA	309mΩ	26.99V	0.034uA	316mΩ
48	26.61V	0.021uA	311mΩ	26.65V	0.032uA	311mΩ
49	26.17V	0.033uA	315mΩ	27.04V	0.033uA	317mΩ
50	26.16V	0.029uA	309mΩ	26.95V	0.025uA	309mΩ
51	26.59V	0.027uA	311mΩ	27.03V	0.021uA	316mΩ
52	26.53V	0.024uA	311mΩ	26.97V	0.028uA	316mΩ
53	26.94V	0.020uA	312mΩ	26.62V	0.022uA	313mΩ
54	27.07V	0.020uA	308mΩ	25.98V	0.024uA	308mΩ
55	26.59V	0.021uA	313mΩ	26.99V	0.032uA	316mΩ
56	26.80V	0.023uA	311mΩ	26.11V	0.022uA	308mΩ
57	26.15V	0.027uA	312mΩ	27.00V	0.029uA	312mΩ
58	26.40V	0.036uA	316mΩ	26.15V	0.035uA	312mΩ

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	26.81V	0.022uA	313mΩ	26.14V	0.028uA	312mΩ
60	25.96V	0.025uA	311mΩ	25.94V	0.032uA	315mΩ
61	26.66V	0.019uA	316mΩ	26.59V	0.032uA	313mΩ
62	25.93V	0.035uA	314mΩ	25.92V	0.031uA	313mΩ
63	26.42V	0.025uA	311mΩ	26.42V	0.032uA	315mΩ
64	26.28V	0.023uA	310mΩ	26.05V	0.022uA	316mΩ
65	27.25V	0.021uA	315mΩ	26.52V	0.032uA	317mΩ
66	26.46V	0.020uA	316mΩ	26.00V	0.025uA	310mΩ
67	26.33V	0.027uA	314mΩ	27.01V	0.028uA	312mΩ
68	26.56V	0.026uA	310mΩ	26.19V	0.029uA	313mΩ
69	26.49V	0.036uA	314mΩ	25.88V	0.022uA	315mΩ
70	26.84V	0.020uA	312mΩ	26.95V	0.017uA	316mΩ
71	25.90V	0.022uA	308mΩ	26.96V	0.024uA	309mΩ
72	27.14V	0.032uA	316mΩ	27.26V	0.031uA	314mΩ
73	27.11V	0.035uA	315mΩ	26.01V	0.025uA	315mΩ
74	27.10V	0.034uA	317mΩ	26.18V	0.018uA	312mΩ
75	26.18V	0.019uA	313mΩ	27.19V	0.024uA	314mΩ
76	26.27V	0.027uA	317mΩ	26.79V	0.023uA	312mΩ
77	25.93V	0.018uA	312mΩ	27.25V	0.018uA	310mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	27.00V	0.029uA	309mΩ	26.76V	0.020uA	312mΩ
2	26.74V	0.027uA	316mΩ	26.80V	0.034uA	308mΩ
3	26.87V	0.023uA	314mΩ	27.19V	0.035uA	311mΩ
4	26.11V	0.034uA	316mΩ	26.32V	0.033uA	316mΩ
5	27.09V	0.019uA	308mΩ	26.50V	0.025uA	312mΩ
6	25.94V	0.031uA	312mΩ	26.30V	0.023uA	316mΩ
7	26.04V	0.027uA	310mΩ	26.65V	0.019uA	310mΩ
8	26.11V	0.030uA	312mΩ	26.28V	0.036uA	315mΩ
9	27.19V	0.020uA	312mΩ	26.61V	0.022uA	310mΩ
10	27.06V	0.018uA	315mΩ	26.03V	0.030uA	312mΩ
11	27.13V	0.030uA	314mΩ	26.88V	0.033uA	310mΩ
12	27.01V	0.035uA	310mΩ	25.89V	0.034uA	314mΩ
13	25.90V	0.019uA	314mΩ	26.95V	0.025uA	313mΩ
13	25.98V	0.036uA	315mΩ	27.27V	0.029uA	310mΩ
15	26.98V	0.024uA	310mΩ	26.03V	0.026uA	311mΩ
16	26.53V	0.024uA	309mΩ	26.61V	0.028uA	308mΩ
17	26.79V	0.020uA	312mΩ	27.17V	0.019uA	315mΩ
18	26.98V	0.024uA	312mΩ	26.56V	0.017uA	312mΩ
19	26.02V	0.020uA	313mΩ	26.51V	0.018uA	314mΩ
20	26.56V	0.019uA	315mΩ	25.92V	0.019uA	312mΩ
21	27.15V	0.031uA	309mΩ	27.25V	0.033uA	314mΩ
22	26.58V	0.033uA	315mΩ	26.57V	0.017uA	309mΩ
23	26.35V	0.021uA	310mΩ	25.94V	0.028uA	310mΩ
24	26.86V	0.033uA	315mΩ	26.47V	0.033uA	315mΩ
25	26.55V	0.033uA	309mΩ	26.65V	0.028uA	310mΩ
26	27.00V	0.019uA	312mΩ	27.10V	0.033uA	313mΩ
27	26.78V	0.030uA	316mΩ	26.57V	0.021uA	316mΩ
28	27.13V	0.035uA	315mΩ	26.71V	0.017uA	316mΩ
29	26.88V	0.024uA	316mΩ	26.16V	0.032uA	315mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	26.86V	0.033uA	314mΩ	26.37V	0.025uA	315mΩ
31	27.24V	0.024uA	310mΩ	26.75V	0.032uA	310mΩ
32	26.54V	0.023uA	315mΩ	26.24V	0.035uA	311mΩ
33	26.60V	0.035uA	313mΩ	27.18V	0.037uA	311mΩ
34	26.25V	0.030uA	310mΩ	26.42V	0.022uA	314mΩ
35	26.62V	0.037uA	311mΩ	26.78V	0.035uA	309mΩ
36	26.11V	0.029uA	314mΩ	26.18V	0.026uA	309mΩ
37	27.12V	0.021uA	313mΩ	26.64V	0.025uA	317mΩ
38	26.84V	0.021uA	310mΩ	26.41V	0.022uA	313mΩ
39	26.45V	0.022uA	311mΩ	25.91V	0.036uA	315mΩ
40	26.16V	0.022uA	313mΩ	26.88V	0.018uA	309mΩ
41	26.04V	0.020uA	313mΩ	26.58V	0.020uA	317mΩ
42	26.67V	0.032uA	314mΩ	26.47V	0.027uA	309mΩ
43	26.47V	0.027uA	315mΩ	26.13V	0.032uA	313mΩ
44	27.15V	0.025uA	312mΩ	26.20V	0.021uA	309mΩ
45	26.65V	0.031uA	310mΩ	26.28V	0.036uA	316mΩ
46	26.02V	0.028uA	315mΩ	26.93V	0.025uA	316mΩ
47	26.50V	0.022uA	314mΩ	27.23V	0.021uA	312mΩ
48	25.91V	0.029uA	315mΩ	27.01V	0.021uA	311mΩ
49	26.85V	0.030uA	316mΩ	26.11V	0.035uA	315mΩ
50	26.75V	0.033uA	315mΩ	27.13V	0.031uA	313mΩ
51	26.99V	0.020uA	310mΩ	26.06V	0.036uA	308mΩ
52	26.60V	0.028uA	316mΩ	25.97V	0.027uA	310mΩ
53	26.07V	0.020uA	313mΩ	27.19V	0.035uA	313mΩ
54	26.07V	0.019uA	313mΩ	27.06V	0.025uA	311mΩ
55	25.98V	0.018uA	311mΩ	26.06V	0.022uA	311mΩ
56	26.07V	0.029uA	313mΩ	26.56V	0.024uA	316mΩ
57	27.06V	0.028uA	315mΩ	25.88V	0.023uA	316mΩ
58	26.82V	0.030uA	315mΩ	26.04V	0.023uA	311mΩ

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs
Test Date: 2017.03.28 ~ 2017.05.10
Test Standard : JESD22 STANDARD Method-A101
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	25.90V	0.026uA	310mΩ	26.26V	0.017uA	313mΩ
60	26.06V	0.031uA	316mΩ	26.61V	0.028uA	309mΩ
61	27.16V	0.031uA	313mΩ	27.05V	0.031uA	311mΩ
62	26.95V	0.020uA	309mΩ	26.31V	0.033uA	315mΩ
63	26.05V	0.020uA	314mΩ	25.92V	0.020uA	314mΩ
64	27.07V	0.022uA	310mΩ	26.66V	0.034uA	313mΩ
65	26.85V	0.030uA	312mΩ	25.88V	0.027uA	316mΩ
66	26.70V	0.020uA	309mΩ	27.25V	0.020uA	313mΩ
67	26.83V	0.017uA	311mΩ	26.29V	0.022uA	310mΩ
68	25.93V	0.033uA	314mΩ	26.82V	0.027uA	313mΩ
69	26.74V	0.036uA	316mΩ	26.40V	0.026uA	315mΩ
70	26.61V	0.022uA	316mΩ	26.42V	0.022uA	315mΩ
71	26.64V	0.034uA	312mΩ	25.96V	0.018uA	315mΩ
72	26.23V	0.028uA	316mΩ	26.48V	0.021uA	315mΩ
73	25.94V	0.029uA	308mΩ	26.90V	0.036uA	315mΩ
74	26.63V	0.037uA	314mΩ	26.94V	0.036uA	308mΩ
75	27.06V	0.018uA	314mΩ	26.80V	0.026uA	312mΩ
76	27.06V	0.022uA	310mΩ	26.29V	0.020uA	316mΩ
77	26.68V	0.018uA	314mΩ	26.50V	0.023uA	312mΩ

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Resistance to Solder Heat Test Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2017.05.12
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
1	26.54V	0.021uA	315mΩ	26.41V	0.024uA	308mΩ
2	26.36V	0.032uA	314mΩ	26.40V	0.033uA	308mΩ
3	27.18V	0.028uA	313mΩ	26.12V	0.021uA	311mΩ
4	26.89V	0.019uA	308mΩ	26.10V	0.029uA	308mΩ
5	26.47V	0.036uA	317mΩ	26.29V	0.020uA	310mΩ
6	26.86V	0.027uA	309mΩ	26.90V	0.034uA	313mΩ
7	26.74V	0.028uA	314mΩ	26.35V	0.020uA	309mΩ
8	27.23V	0.021uA	315mΩ	26.11V	0.035uA	309mΩ
9	25.88V	0.025uA	314mΩ	27.00V	0.020uA	311mΩ
10	26.43V	0.018uA	313mΩ	26.29V	0.018uA	315mΩ
11	27.06V	0.031uA	315mΩ	27.01V	0.021uA	309mΩ
12	26.48V	0.027uA	312mΩ	27.05V	0.022uA	314mΩ
13	26.03V	0.023uA	315mΩ	26.04V	0.032uA	316mΩ
13	26.53V	0.022uA	309mΩ	26.62V	0.020uA	311mΩ
15	25.95V	0.032uA	311mΩ	26.36V	0.021uA	308mΩ
16	25.94V	0.035uA	316mΩ	26.49V	0.022uA	310mΩ
17	26.39V	0.034uA	312mΩ	26.65V	0.036uA	310mΩ
18	26.51V	0.034uA	315mΩ	26.05V	0.029uA	312mΩ
19	26.33V	0.018uA	311mΩ	26.23V	0.017uA	312mΩ
20	26.77V	0.023uA	309mΩ	26.26V	0.025uA	308mΩ
21	26.07V	0.019uA	312mΩ	26.67V	0.020uA	315mΩ
22	26.30V	0.017uA	313mΩ	26.36V	0.033uA	313mΩ
23	26.06V	0.019uA	317mΩ	26.09V	0.018uA	317mΩ
24	25.90V	0.031uA	310mΩ	26.94V	0.020uA	317mΩ
25	25.95V	0.029uA	309mΩ	25.92V	0.022uA	314mΩ
26	26.58V	0.028uA	309mΩ	27.15V	0.024uA	315mΩ
27	26.53V	0.026uA	310mΩ	27.25V	0.032uA	317mΩ
28	26.56V	0.021uA	316mΩ	26.60V	0.028uA	310mΩ
29	26.86V	0.032uA	316mΩ	25.94V	0.024uA	314mΩ

SeCoS Corporation

Resistance to Solder Heat Test Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2017.05.12
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
30	26.68V	0.019uA	309mΩ	26.78V	0.023uA	310mΩ
31	26.59V	0.018uA	311mΩ	26.23V	0.025uA	309mΩ
32	26.16V	0.035uA	316mΩ	26.14V	0.019uA	315mΩ
33	25.93V	0.033uA	312mΩ	26.08V	0.017uA	310mΩ
34	27.14V	0.017uA	313mΩ	26.24V	0.021uA	316mΩ
35	26.77V	0.029uA	312mΩ	26.95V	0.031uA	309mΩ
36	26.14V	0.024uA	316mΩ	26.40V	0.019uA	315mΩ
37	26.33V	0.017uA	315mΩ	26.06V	0.036uA	313mΩ
38	26.76V	0.030uA	311mΩ	26.46V	0.021uA	317mΩ
39	26.59V	0.021uA	314mΩ	27.27V	0.021uA	316mΩ
40	26.84V	0.022uA	310mΩ	26.26V	0.036uA	310mΩ
41	26.78V	0.032uA	312mΩ	27.26V	0.029uA	315mΩ
42	27.08V	0.034uA	310mΩ	26.48V	0.020uA	311mΩ
43	26.36V	0.037uA	310mΩ	26.22V	0.018uA	315mΩ
44	26.49V	0.032uA	309mΩ	27.20V	0.036uA	316mΩ
45	26.49V	0.033uA	312mΩ	26.26V	0.034uA	313mΩ
46	26.21V	0.035uA	313mΩ	27.09V	0.023uA	313mΩ
47	26.12V	0.019uA	313mΩ	26.49V	0.034uA	312mΩ
48	27.17V	0.025uA	308mΩ	26.78V	0.023uA	316mΩ
49	26.64V	0.033uA	312mΩ	26.28V	0.017uA	312mΩ
50	26.88V	0.031uA	314mΩ	26.84V	0.019uA	309mΩ
51	26.72V	0.033uA	311mΩ	25.97V	0.029uA	314mΩ
52	25.90V	0.028uA	311mΩ	25.92V	0.018uA	310mΩ
53	26.11V	0.025uA	314mΩ	27.25V	0.020uA	314mΩ
54	25.96V	0.026uA	313mΩ	26.34V	0.033uA	317mΩ
55	25.94V	0.027uA	317mΩ	26.24V	0.034uA	309mΩ
56	26.93V	0.032uA	310mΩ	26.01V	0.022uA	312mΩ
57	25.93V	0.025uA	309mΩ	26.24V	0.031uA	314mΩ
58	26.70V	0.021uA	315mΩ	26.51V	0.023uA	313mΩ

SeCoS Corporation

Resistance to Solder Heat Test Test Data

Report No : T170512-102
Part No : SSN3134K-C
Test Equipment: JUNO Test System DTS-1000
Test Condition : 20V <V(BR)DSS @ID=250μA ；IDSS < 1.0μA@VDS=20V
RDS(ON) < 380mΩ@VGS=4.5V, ID=650mA
Test Condition: 270℃ ± 5℃, 7Sec + 2Sec/-0Sec
Test Date: 2017.05.12
Test Standard : JESD22 STANDARD Method-B106
Operator: Leo Hsia

Test Result: PASS

	Before			After		
No	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$	$V_{(BR)DSS}$	I_{DSS}	$R_{DS(ON)}$
59	26.86V	0.029uA	313mΩ	26.26V	0.024uA	315mΩ
60	26.61V	0.017uA	311mΩ	26.53V	0.019uA	314mΩ
61	26.81V	0.019uA	315mΩ	26.92V	0.033uA	308mΩ
62	26.22V	0.018uA	310mΩ	26.24V	0.033uA	316mΩ
63	27.15V	0.024uA	315mΩ	26.87V	0.029uA	308mΩ
64	26.92V	0.031uA	314mΩ	26.94V	0.031uA	311mΩ
65	26.82V	0.033uA	315mΩ	27.19V	0.018uA	311mΩ
66	27.21V	0.021uA	310mΩ	26.15V	0.034uA	315mΩ
67	25.96V	0.032uA	310mΩ	26.21V	0.022uA	312mΩ
68	26.98V	0.025uA	312mΩ	27.26V	0.029uA	310mΩ
69	26.48V	0.028uA	308mΩ	25.92V	0.028uA	311mΩ
70	27.09V	0.029uA	315mΩ	26.71V	0.023uA	311mΩ
71	26.04V	0.019uA	309mΩ	26.91V	0.035uA	312mΩ
72	26.71V	0.024uA	314mΩ	26.44V	0.028uA	311mΩ
73	26.47V	0.029uA	313mΩ	26.43V	0.024uA	314mΩ
74	26.01V	0.027uA	317mΩ	26.08V	0.028uA	309mΩ
75	25.99V	0.026uA	312mΩ	25.92V	0.019uA	316mΩ
76	26.79V	0.034uA	311mΩ	25.97V	0.030uA	312mΩ
77	26.09V	0.035uA	314mΩ	26.73V	0.034uA	311mΩ

Made By: King Huang

Approval: Peter Yang